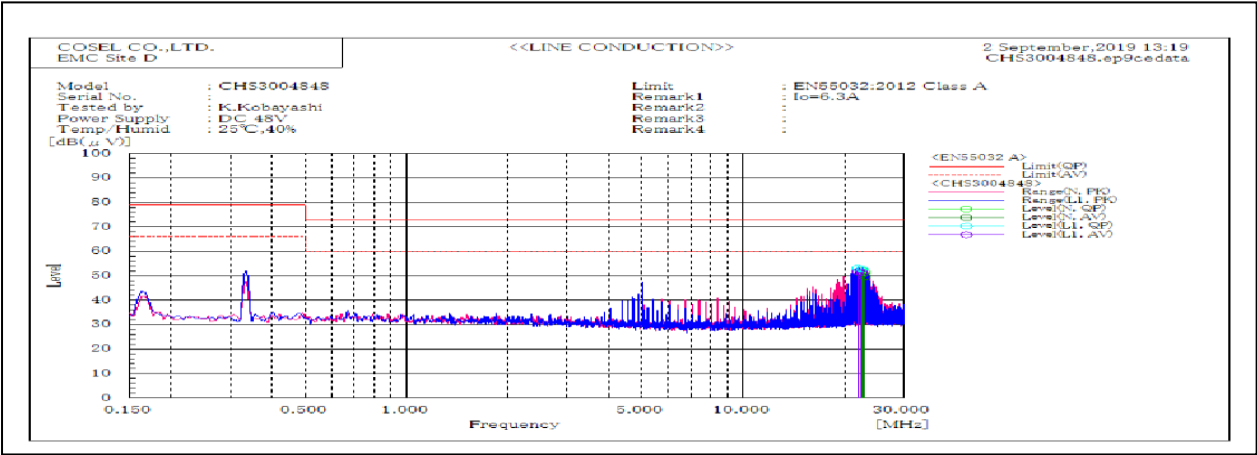
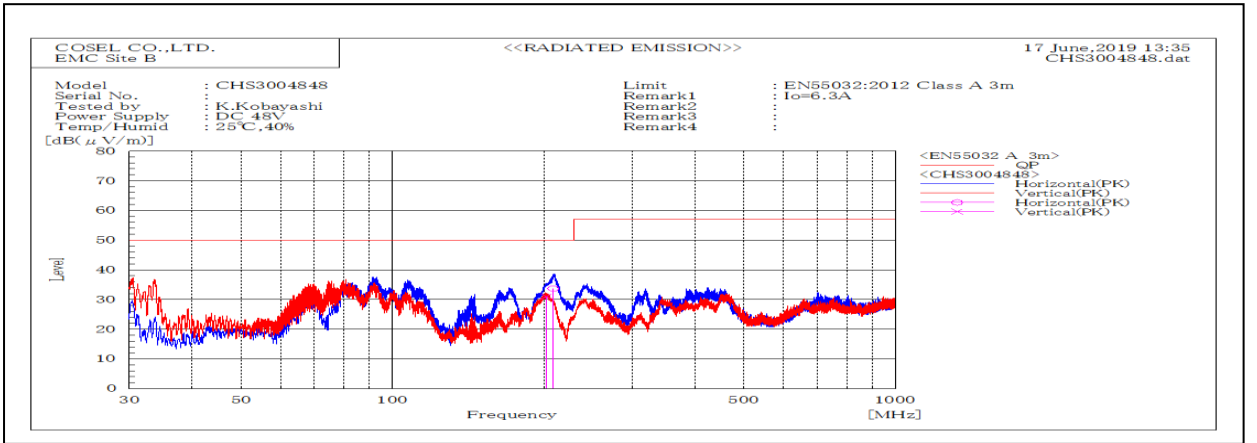


DATA SHEET		Date	02-Sep-19
Model	CHS3004848	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi



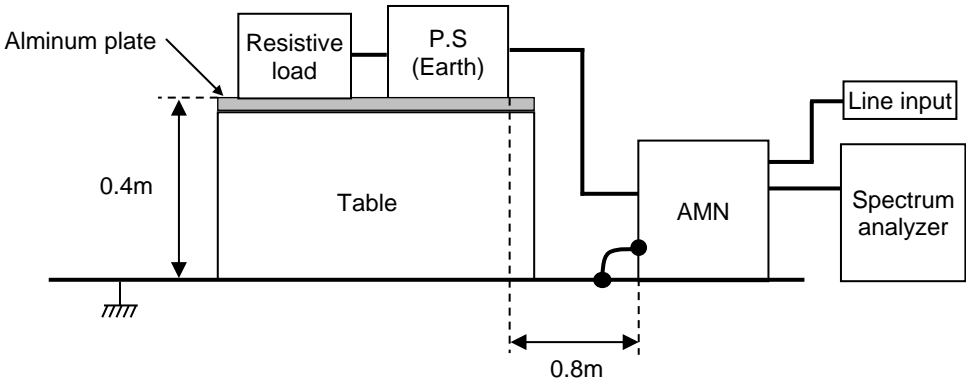
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
22.56	N	52.2	50.7	73.0	60.0	20.8	9.3	Pass	
22.90	N	51.4	49.6	73.0	60.0	21.6	10.4	Pass	
21.89	L1	53.1	51.6	73.0	60.0	19.9	8.4	Pass	
22.56	L1	52.9	51.4	73.0	60.0	20.1	8.6	Pass	



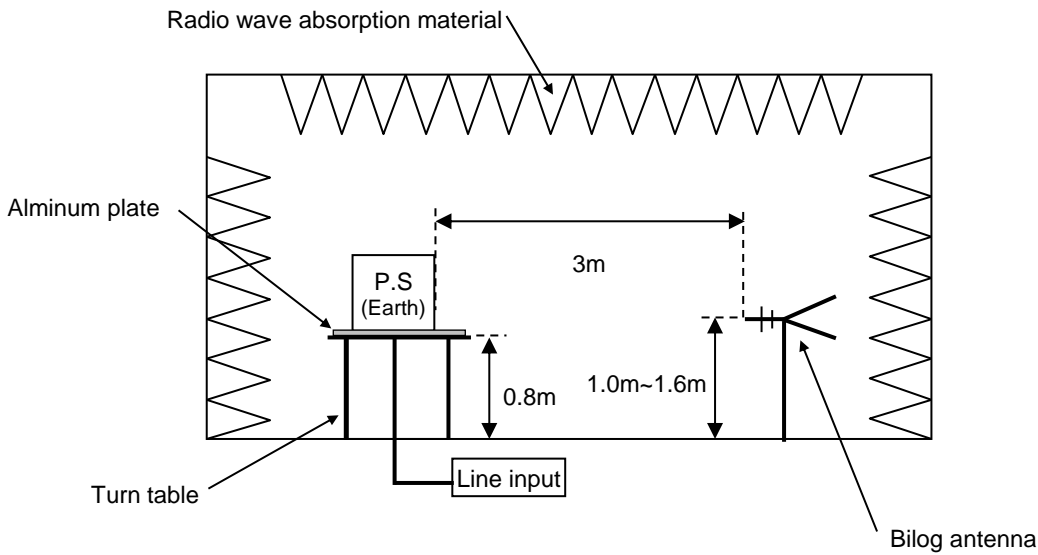
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
208.92	H	Stable	33.7	50.0	16.3	Pass	161.9	10.0	
201.97	V	Stable	31.0	50.0	19.0	Pass	100.0	159.5	

DATA SHEET		Date	02-Sep-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

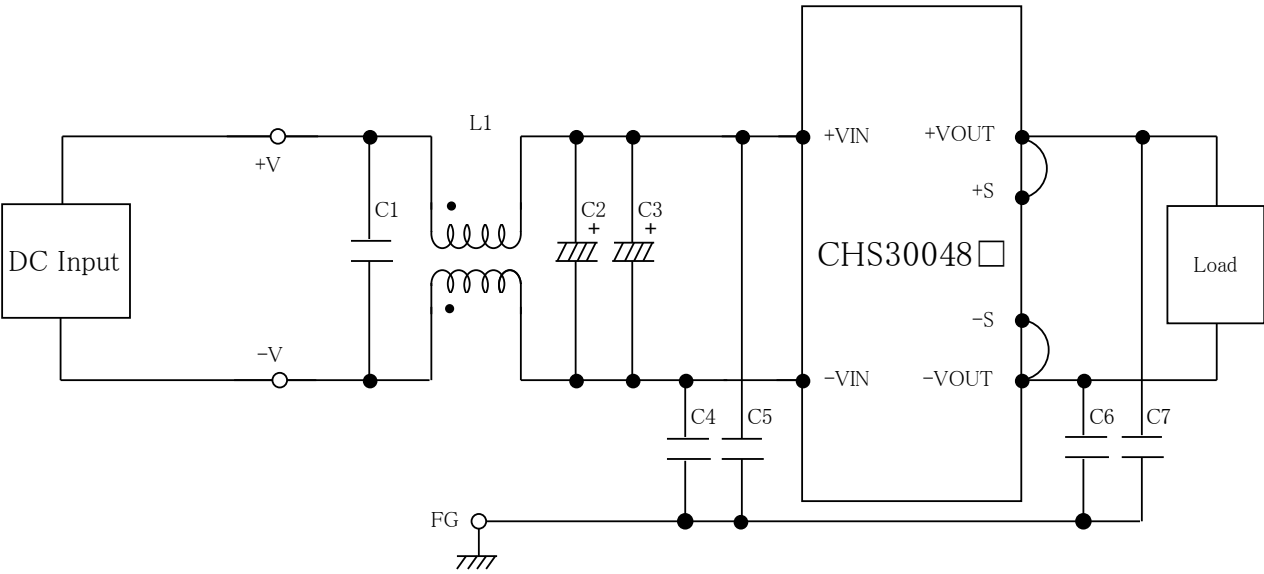


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C3 : 100V 100 μ F PWseries (nichicon)
- C4,C5 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C6,C7 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)